Asigurarea Calitatii – Quality Assurance, ISSN 1224–5410
Vol. XXII, Issue 86, April-June 2016
Pages 16-20

Fault Modeling, Fault Tolerance, and Test

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Abstract
Fault diagnosis of ICs is essential to reduce design iterations in order to meet the time-to-market goal of the first prototypes. The paper takes a fresh look at lessons learned and where things stand today, along with prospects for a next future.

Keywords: MOS, VLSI, fault models and model faults, fault diagnosis, testing strategy

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